

# Allpix2

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General



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# Simulation pipeline

```
1. [Allpix]
2. random_seed_core = 0
3. # Log level is set to INFO
4. log_level = "WARNING"
5. # Use the default logging format
6. log_format = "DEFAULT"
7. # Location of the detector configuration
8. detectors_file = "luxegbp_detector.conf"
9. # Simulate a total of 10000 events
10. number_of_events = 1000000

11. [GeometryBuilderGeant4]
12. world_material = "air"

13. # Initialize physics list and particle source
14. [DepositionGeant4]
15. # Use a Geant4 physics lists with EMPhysicsStandard_optio
16. physics_list = FTFP_BERT_LIV
17. # Use a photon as particle
18. particle_code = 22
19. # particle_type = "Pi+"
20. # Set the energy of the particle
21. source_energy = 1GeV
22. # Origin of the beam
23. source_position = 0 0 -100
24. # The direction of the beam
25. beam_direction = 0 0 1
26. # Use a single particle in a single 'event'
27. number_of_particles = 1
28. # Energy needed to create a charge deposit
29. charge_creation_energy = 27eV
30. source_type = "beam"
31. # source_type = "point"
32. beam_size = 1320um
33. # Limit the maximal step length
34. # max_step_length = 1um
35. # Output plots
36. output_plots = true

37. # Set up a constant electric output plots field
38. [ElectricFieldReader]
39. model = "custom"
40. field_function = "[0]"
41. field_parameters = 50000V/mm
42. output_plots = true
43. # Adds a weighting potential (Ramo potential) to the detector.
44. # The potential was evaluated with the luxegbp.conf model
45. # [WeightingPotentialReader]
46. # name = "detStripX"
47. # model = "mesh"
48. # file_name = "gbp_weightingpotential.apf"
49. # output_plots = true

50. # Adds a doping profile to the detector
```

Geometry is written in the `_detector.conf` file.

Module which deposits charge carriers in the active volume of all detectors. It acts as wrapper around the Geant4 logic and depends on the global geometry constructed by the `GeometryBuilderGeant4` module. It initializes the physical processes to simulate a particle source that will deposit charge carriers for every event simulated. The number of electron/hole pairs created is calculated using the mean pair creation energy `charge_creation_energy`, fluctuations are modeled using a Fano factor `fano_factor` assuming Gaussian statistics.

As first approximation, the initial beam is modelled as a gaussian beam, whose characteristics are extracted from the realistic beam ptarmigan data.

Electrostatic field produced by the biasing voltage is calculated and stored in a dat file. However, early simulations adopted a constant E field to speed up computation times

```
51. # This module is necessary in order to enable the finite carrier lifetime
52. [DopingProfileReader]
53. # For now it is assumed as a constant uniform
54. model = "constant"
55. # The value is related to the carrier lifetime by the recombination_model.
56. # The 1e20 value corresponds to an electron lifetime of 1 ns
57. doping_concentration = 1e20/cm/cm/cm
```

Doping concentration is related to carriers lifetime by the recombination model (67)

```
58. # Propagate the charge carriers through the sensor
59. [GenericPropagation]
60. # Set the temperature of the sensor (defaults to room temperature 293.15K)
61. temperature = 300K
62. # Charge carrier mobility model to be used for the propagation. Defaults to jacoboni
63. mobility_model = "jacoboni"
64. # Propagate multiple charges at once
65. # charge_per_step = 10
66. # Recombination model
67. recombination_model = "srh"
68. # Determines if simple output plots should be generated for a monitoring of the simulation flow.
69. output_plots = true
70. #output_linegraphs = true
71. #output_animations = true
```

Simulates the propagation of electrons and/or holes through the sensitive sensor volume of the detector. The propagation consists of a combination of drift and diffusion simulation.

```
72. # Transfer the propagated charges to the pixels
73. [SimpleTransfer]
74. max_depth_distance = 100um
75. output_plots = true
```

Combines individual sets of propagated charges together to a set of charges on the sensor strips and thus prepares them for processing by the detector front-end electronics.

```
76. # Simple digitization module which translates the collected charges into a digitized signal proportional to the input charge.
77. [DefaultDigitizer]
78. # Noise added by the readout electronics
79. #electronics_noise = 100e
80. # Threshold for a hit to be detected (see line 359 of LUXE_tech_note_template.pdf)
81. #threshold = 62500e
82. # Threshold dispersion
83. # threshold_smearing = 30e
84. # Noise added by the digitisation
85. # qdc_smearing = 100e
86. #qdc_resolution = 12
87. #output_plots = true
88. #output_plots_scale = 30ke
89. #output_plots_bins = 100
```

```
90. [DetectorHistogrammer]
91. name = "detStripX"

92. #[ROOTObjectWriter]
93. #file_name = "output_gbp.root"
```

# Deposited charge

- The number of electron/hole pairs created is calculated using the mean pair creation energy in sapphire (27 eV) [1]. Fluctuations are modeled using a Fano factor (0.115) assuming Gaussian statistics. [2]
- As first approximation of the initial particle beam, a gaussian beam was used. Its parameters were extracted fitting the realistic beam from Ptarmigan.
- Accurate reproduction of the initial beam can be implemented, in an analogous manner of what done in Geant4 StandaloneGBP. This requires 10 days of work (not spoiling multi-threading requires special care)

# Electrostatic field

- The external electrostatic field in the detector – i.e. not including polarisation effects produced during charge transport – can be calculated numerically with a tool which comes with allpix2. The computation needs to be made once and it takes 12/24 hours.

Detector geometry and the bias voltage are the inputs of the E-field computation. The output is a INIT/APF file (the former is compatible with PixelAV) with a 3d map of the vector field.

- The electrostatic field is imported via the “ElectricFieldReader” module which allows to implement the E field either with a constant/parametric formula or by reading the E field from a file.
- At present time, for the preliminary simulation a constant E field of intensity 5 V/ $\mu\text{m}$  is used. Polarisation effects – e.g. local E-field produced by trapped charges – are not accounted yet. They may be encompassed by using a E-field profile quadratic in the sensor thickness  $z$  (as done in ref. [\[1\]](#))

# Charge carrier propagation

- The [DepositionGeant4] module produces charge carriers.
- Electrons & holes are then propagated toward the collecting implants with a drift/diffusion model.
- Jacoboni-Canali model is the one used.
- Default silicon parameters are replaced with the sapphire parameters from [1] e [3]. Some adaptations were needed since the two models are different

## 6.1.1 Jacoboni-Canali Model

The Jacoboni-Canali model [25] is the most widely used parametrization of charge carrier mobility in Silicon as a function of the electric field  $E$ . It has originally been derived for  $\langle 111 \rangle$  silicon lattice orientation, but is widely used also for the common  $\langle 100 \rangle$  orientation. The mobility is parametrized as

$$\mu(E) = \frac{v_m}{E_c} \frac{1}{(1 + (E/E_c)^\beta)^{1/\beta}}, \quad (6.1)$$

where  $v_m$ ,  $E_c$ , and  $\beta$  are phenomenological parameters, defined for electrons and holes respectively. The temperature dependence of these parameters is taken into account by scaling them with respect to a reference parameter value as

$$A = A_{ref} \cdot T^\gamma \quad (6.2)$$

where  $A_{ref}$  is the reference parameter value,  $T$  the temperature in units of K, and  $\gamma$  the temperature scaling factor.

The parameter values implemented in Allpix<sup>2</sup> are taken from Table 5 of [25] as:

$$\begin{aligned} v_{m,e} &= 1.53 \times 10^9 \cdot T^{-0.87} \text{ cm/s} & v_{m,h} &= 1.62 \times 10^8 \cdot T^{-0.52} \text{ cm/s} \\ E_{c,e} &= 1.01 \cdot T^{1.55} \text{ V/cm} & E_{c,h} &= 1.24 \cdot T^{1.68} \text{ V/cm} \\ \beta_e &= 2.57 \times 10^{-2} \cdot T^{0.66} & \beta_h &= 0.46 \cdot T^{0.17} \end{aligned}$$

for electrons and holes, respectively.

# Charge carriers. Literature

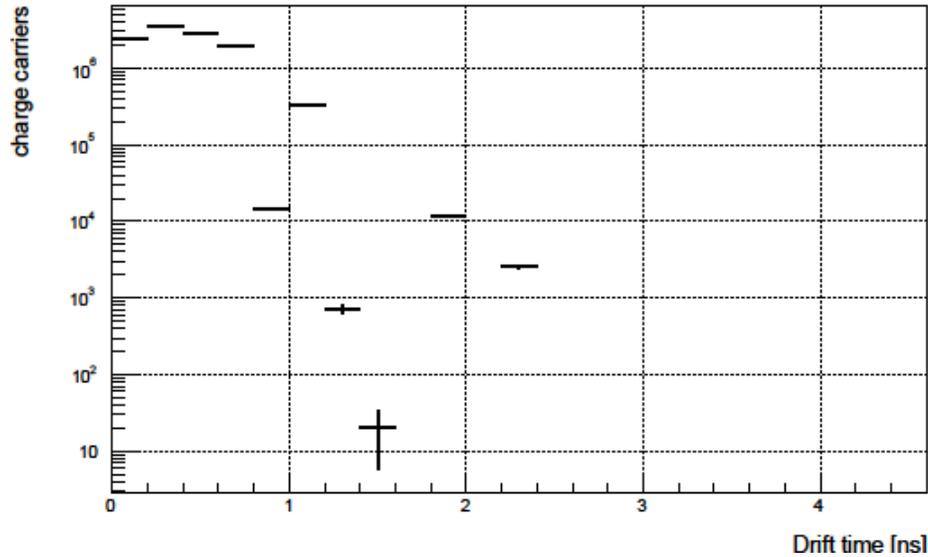
- From reference [3] one reads...
  - the room temperature mobility of electrons (holes) as  $\mu_e \sim 600 \text{ cm}^2/\text{Vs}$  ( $\mu_h = 60$ )
  - that at 40K the e<sup>-</sup> mobility is  $\sim 30000 \text{ cm}^2/\text{Vs}$  in high purity sapphire (in Si it holds  $\mu = AT^{-\gamma}$  with  $A=1.43 \cdot 10^9$  and  $\gamma=2.42$  for temperatures  $T \geq 50 \text{ K}$ )
  - that *impurities play a role* constraining chg. mobility to  $\sim 4000 \text{ cm}^2/\text{Vs}$
- In reference [1]...
  - polarisation effects, i.e. internal electric field produced by trapped charges, are accounted using a resulting electric field with parabolic shape ( $E = A(y-d/2)^2 + B$ )
  - the drift velocity is assumed to be directly proportional to the electric field strength ( $v_{ni_e} = \mu_e E(y)$ )
  - charge carrier lifetime is assumed to be constant  $\tau_e = \text{const.}$
  - in the case where the mean lifetime is much smaller than the time necessary to travel to the implants, there is a dependence of the CCE from the biasing voltage  $V$
  - a fraction ( $\sim 0.5$ ) of charge carriers recombines immediately after creation

# Simulation time & output data

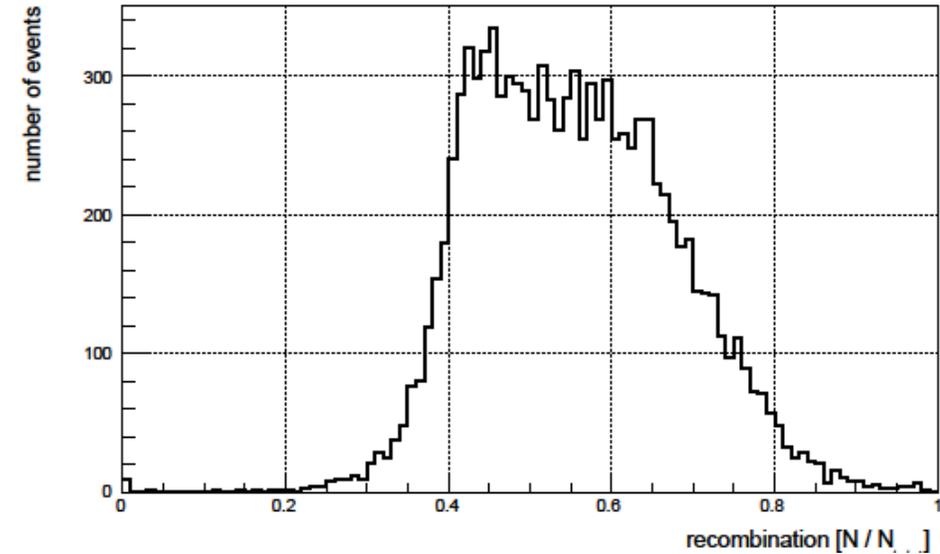
- By default, Allpix2 outputs a small ( $\sim 3$  MB) summary in ROOT format
  - It contains a list of predefined histograms to inspect each module (e.g. DepositionGeant4, GenericPropagation, etc.).
- If called, the module 'ROOTObjectWriter' record all the 'raw' simulation data in a ROOT file (size  $\sim 0.5$  GB).
  - The summary report can be reconstructed by using ROOT macros.
  - Allpix2 symbols allow for a deeper analysis using the 'raw' data
- Simulation bottleneck is in the file I/O:
  - summary only ( $\sim$  **4 minutes**)
  - with 'raw' root file ( $\sim$  **3.3 days**)
- It is important to set the quantities of interest, in order to optimize simulation time by reducing file IO. For instance I focused over observables for studying the CCE; charge recombination; and the best operating conditions

# Preliminary results

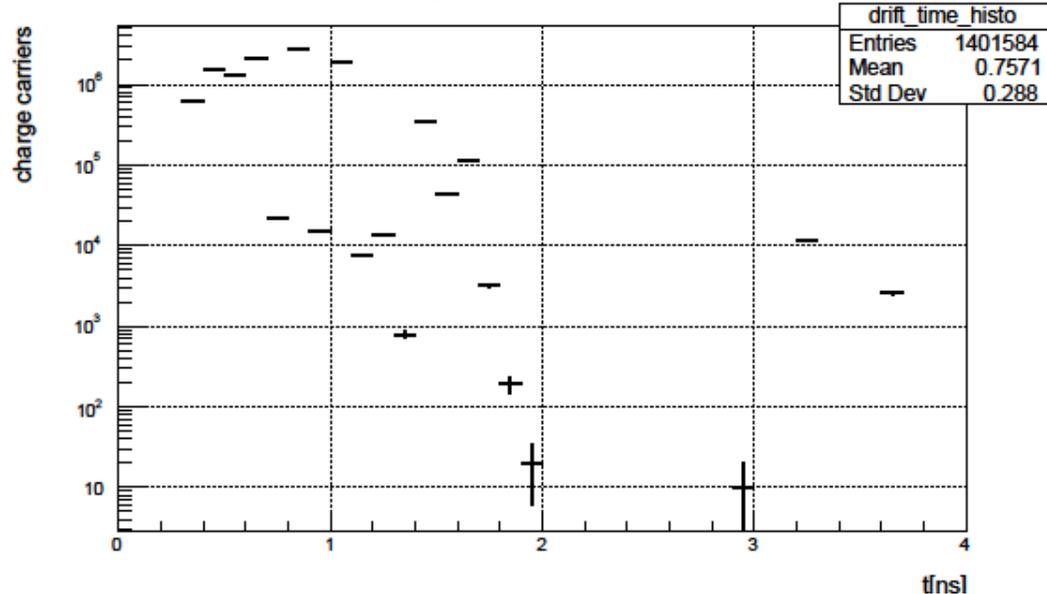
Drift time



Fraction of recombined charge carriers



Charge carrier arrival time



- In each step, charge carrier lifetime ( $\tau$ ) is determined and a survival probability is calculated: a random  $0 \leq r \leq 1$  is compared with  $dt / \tau$  with  $dt$  the time step of the last charge carrier movement